A semiconductor laser device is characterized in that

an angle θ of inclination formed by the side surfaces of a ridge portion and a lower part of the ridge portion is at least 70° and not more than 117°, a p-type cladding layer is made of $Al_{x_1}Ga_{1-x_1}As$, a first current blocking layer is made of $Al_{x_2}Ga_{1-x_2}As$, the distance between an emission layer and the first current blocking layer satisfies the relation of t \leq 0.275/(1 - (X2 - X1)) assuming that t represents the distance, and a lower width W of the ridge portion is at least 2 μ m and not more than 5 μ m.

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